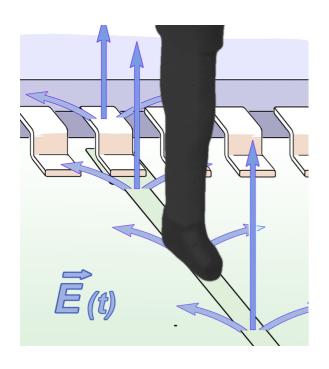
RF-E 05 E-Field Probe 30 MHz up to 3 GHz





Short description

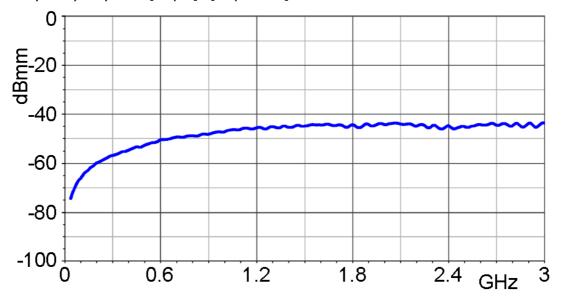
The electrode at the underside of the probe head of the RF-E 05 has a width of approx. 0.5 mm. The E-fields of clocked lines, IC pins, and smaller components are precisely located. The RF-E 05 probe was developed for Langer scanner.

The RF-E 05 is a near-field probe. It has the same structure as the RF-E 02 and RF-E 10 probes, but detects E-fields from very small ranges. The RF-E 05 is designed to detect the specific cause of an electrical interference field. For measurements the E-field probe is positioned directly onto or held above the components or surfaces of printed circuit boards. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω .

Technical parameters

| Frequency range | 30 MHz 3 GHz |
|------------------------|-----------------|
| Resolution | ≈ 0.6 mm |
| Probe head dimensions: | ≈ (1 x 8) mm |
| Connector - output | SMB, male, jack |

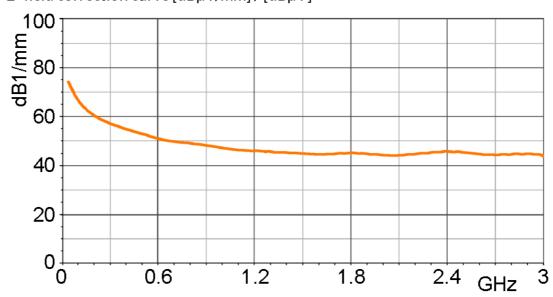
Frequency response [dBµV] / [dBµV/mm]



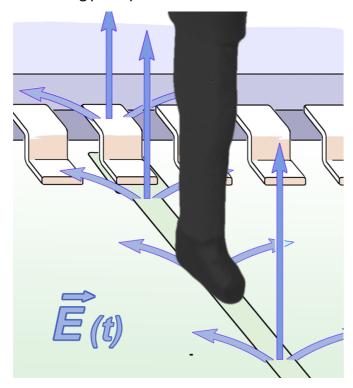
RF-E 05 E-Field Probe 30 MHz up to 3 GHz



E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



RF-E 05 E-Field Probe 30 MHz up to 3 GHz



Probe head

